

# SLN30P03T

## -30V P -Channel MOSFET

### General Description

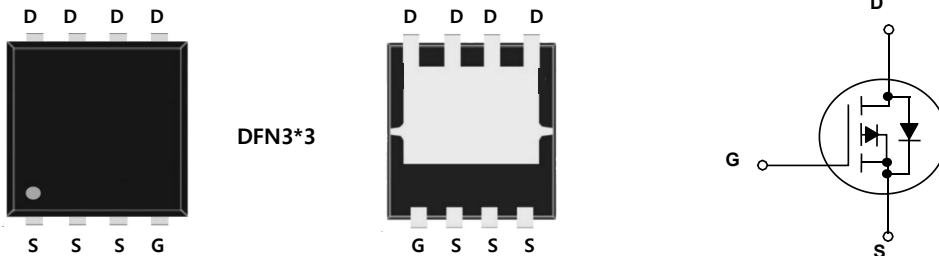
This Power MOSFET is produced using Maple semi's advanced planar stripeTRENCH technology. This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

### Features

- P-Channel:-30V -35A
- $R_{DS(on)Typ} = 8m\Omega @ V_{GS} = -10V$
- $R_{DS(on)Typ} = 13m\Omega @ V_{GS} = -4.5V$
- Very Low On-resistance RDS(ON)
- LowCrss
- Fast switching
- 100% avalanche tested

### Application

- PWM Application
- Load Switch
- Power Management



### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol          | Parameter   | SLN30P03T   | Units               |
|-----------------|---|-------------|---------------------|
| $V_{DSS}$       | Drain-Source Voltage  | -30         | V                   |
| $I_D$           | Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )<br>- Continuous ( $T_C = 100^\circ\text{C}$ ) | -35         | A                   |
|                 |   | -23         | A                   |
| $I_{DM}$        | Drain Current - Pulsed (Note 1)   | -140        | A                   |
| $V_{GSS}$       | Gate-Source Voltage   | $\pm 20$    | V                   |
| $E_{AS}$        | Single Pulsed Avalanche Energy  | 78.8        | mJ                  |
| $P_D$           | Power Dissipation ( $T_C = 25^\circ\text{C}$ )  | 21.5        | W                   |
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case  | 5.8         | W/ $^\circ\text{C}$ |
| $T_J, T_{STG}$  | Operating and Storage Temperature Range   | -55 to +150 | $^\circ\text{C}$    |
| $T_L$           | Maximum lead temperature for soldering purposes,<br>1/8" from case for 5 seconds                      | 300         | $^\circ\text{C}$    |

\* Drain current limited by maximum junction temperature.

**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

**Off Characteristics**

|            |                                    |  |     |    |      |               |
|------------|------------------------------------|--|-----|----|------|---------------|
| $BV_{DSS}$ | Drain-Source Breakdown Voltage     | $V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$ | -30 | -- | --   | V             |
| $I_{DSS}$  | Zero Gate Voltage Drain Current    | $V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}$         | --  | -- | -1   | $\mu\text{A}$ |
| $I_{GSSF}$ | Gate-Body Leakage Current, Forward | $V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$          | --  | -- | -100 | nA            |
| $I_{GSSR}$ | Gate-Body Leakage Current, Reverse | $V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$         | --  | -- | 100  | nA            |

**On Characteristics**

|              |                                   |  |      |      |      |                  |
|--------------|-----------------------------------|--|------|------|------|------------------|
| $V_{GS(th)}$ | Gate Threshold Voltage            | $V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$ | -1.0 | -1.5 | -2.5 | V                |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS} = -10\text{ V}, I_D = -12\text{ A}$      | --   | 8    | 11   | $\text{m}\Omega$ |
|              |                                   | $V_{GS} = -4.5\text{ V}, I_D = -8\text{ A}$      | -    | 13   | 16.5 |                  |

**Dynamic Characteristics**

|            |                              |   |    |      |   |             |
|------------|------------------------------|---|----|------|---|-------------|
| $C_{iss}$  | Input Capacitance            | $V_{DS} = -15\text{ V}, V_{GS} = 0\text{ V},$<br>$f = 1.0\text{ MHz}$ | -- | 2800 | - | $\text{pF}$ |
| $C_{oss}$  | Output Capacitance           |   | -- | 346  | - | $\text{pF}$ |
| $C_{riss}$ | Reverse Transfer Capacitance |   | -- | 319  | - | $\text{pF}$ |

**Switching Characteristics**

|              |                     |  |    |     |    |    |
|--------------|---------------------|--|----|-----|----|----|
| $t_{d(on)}$  | Turn-On Delay Time  | $V_{GS} = -10\text{ V}, V_{DS} = -15\text{ V},$<br>$R_G = 2.5\text{ }\Omega, I_D = -20\text{ A}$ | -- | 14  | -- | ns |
| $t_r$        | Turn-On Rise Time   |  | -- | 20  | -- | ns |
| $t_{d(off)}$ | Turn-Off Delay Time |  | -- | 95  | -- | ns |
| $t_f$        | Turn-Off Fall Time  |  | -- | 65  | -- | ns |
| $Q_g$        | Total Gate Charge   | $V_{DS} = -15\text{ V}, I_D = -20\text{ A},$<br>$V_{GS} = -10\text{ V}$                          | -- | 30  | -- | nC |
| $Q_{gs}$     | Gate-Source Charge  |  | -- | 5.3 | -- | nC |
| $Q_{gd}$     | Gate-Drain Charge   |  | -- | 7.6 | -- | nC |

**Drain-Source Diode Characteristics and Maximum Ratings**

|          |   |    |    |      |   |
|----------|---|----|----|------|---|
| $I_S$    | Maximum Continuous Drain-Source Diode Forward Current   | -- | -- | -10  | A |
| $I_{SM}$ | Maximum Pulsed Drain-Source Diode Forward Current   | -- | -- | -40  | A |
| $V_{SD}$ | Drain to Source Diode Forward Voltage, $V_{GS} = 0\text{ V}, I_{SD} = -10\text{ A}, T_J = 25^\circ\text{C}$ | -- | -- | -1.2 | V |

**Notes:**

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition:  $T_J = 25^\circ\text{C}, V_{DD} = 20\text{ V}, V_G = -10\text{ V}, R_G = 25\text{ }\Omega, L = 0.5\text{ mH}, I_{AS} = -17\text{ A}$
3. Pulse Test: Pulse Width  $\leq 300\text{ }\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$

### P- Channel Typical Characteristics

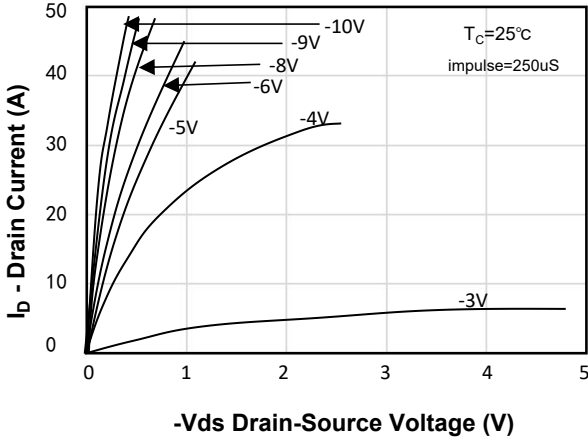


Figure 1. On-Region Characteristics

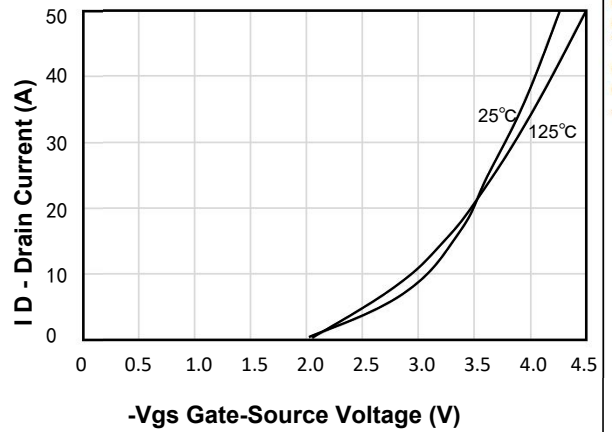


Figure 2. Transfer Characteristics

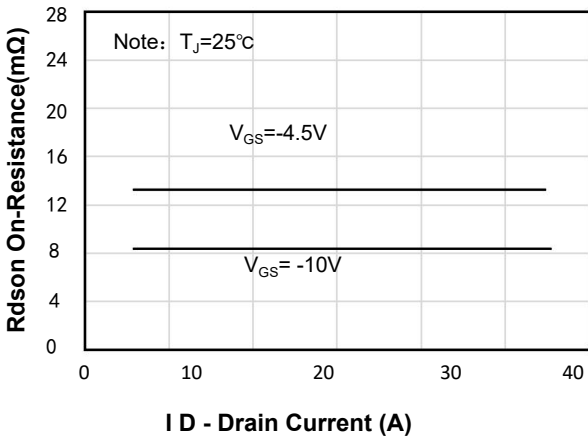


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

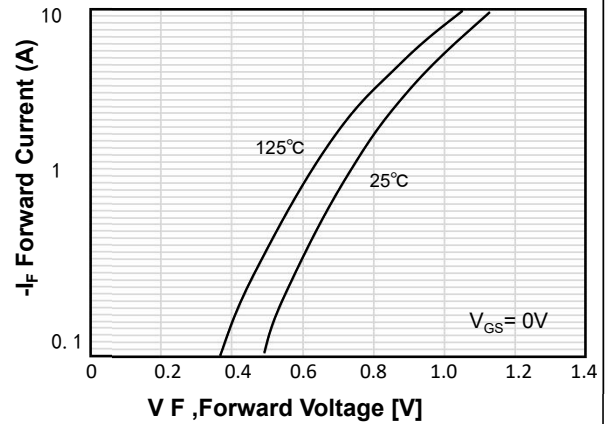


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

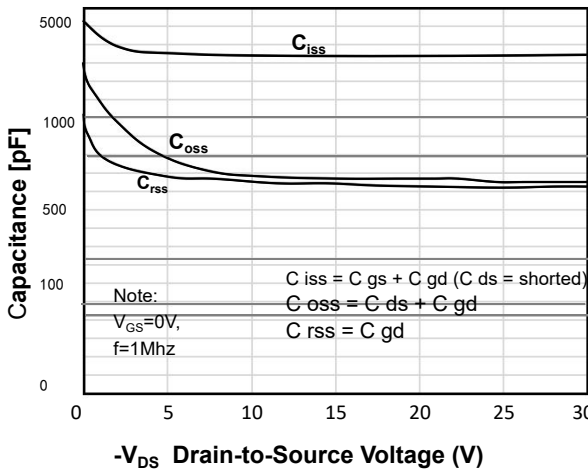


Figure 5. Capacitance Characteristics

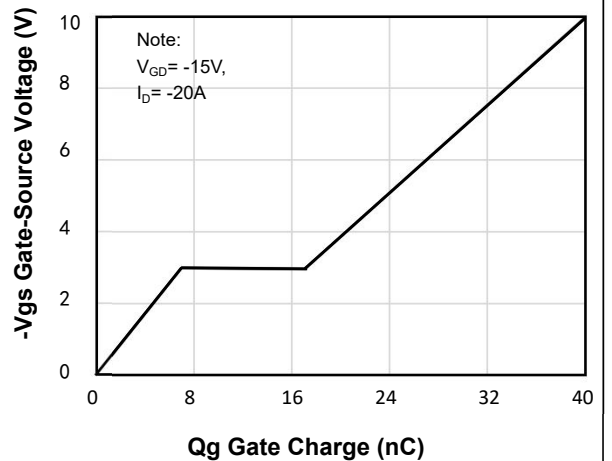
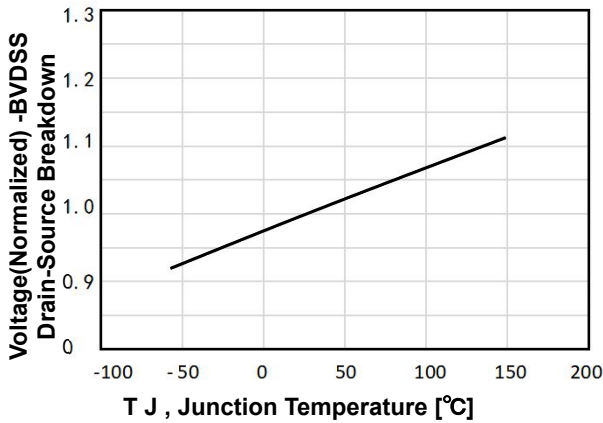
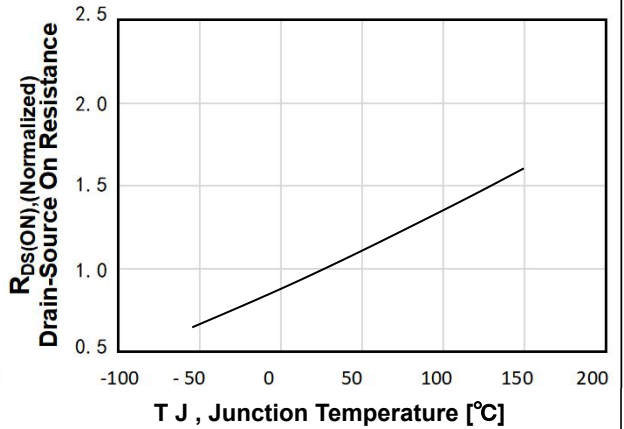


Figure 6. Gate Charge Characteristics

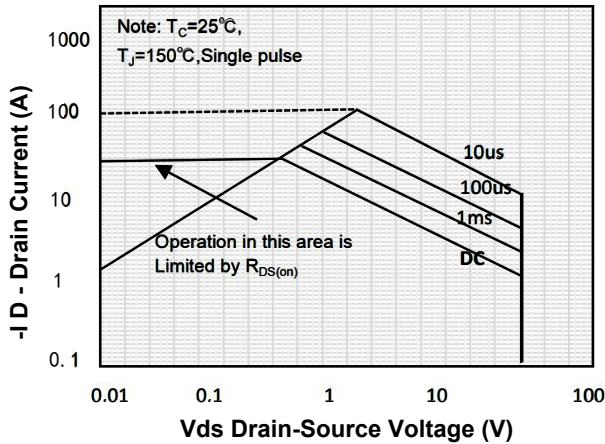
**P- Channel Typical Characteristics** (Continued)



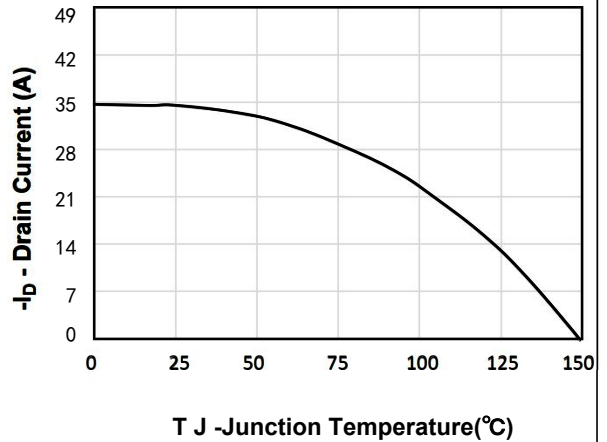
**Figure 7. Breakdown Voltage Variation vs Temperature**



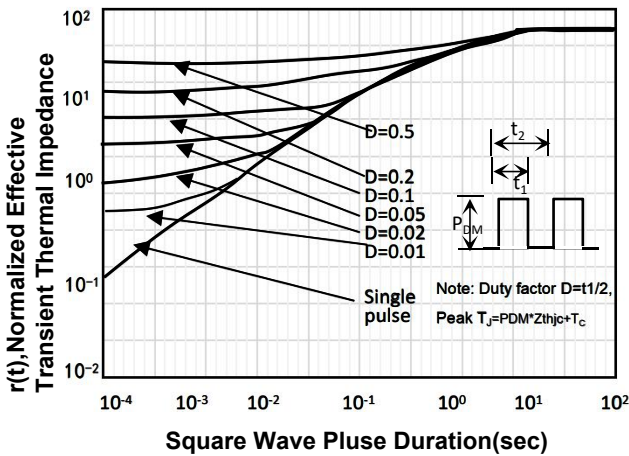
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Maximum Safe Operating Area**

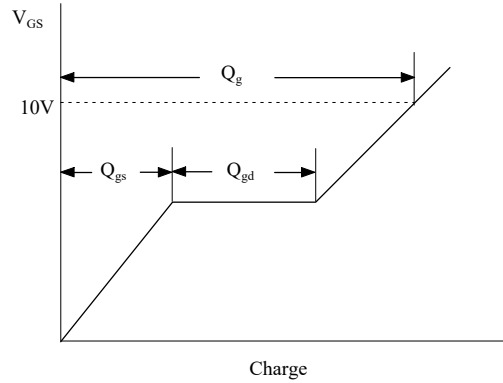


**Figure 10. Maximum PContinuous Drain Current vs Case Temperature**

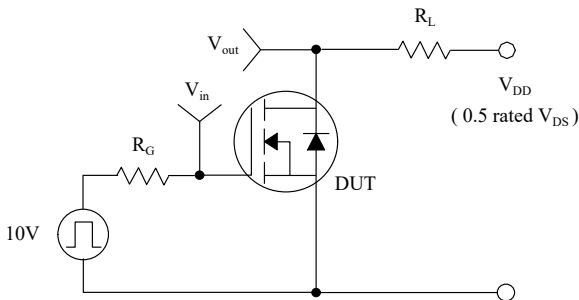


**Figure 11. Transient Thermal Response Curve**

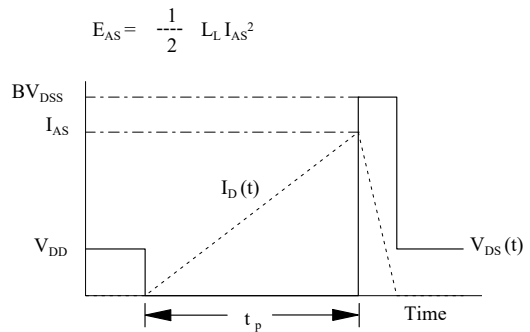
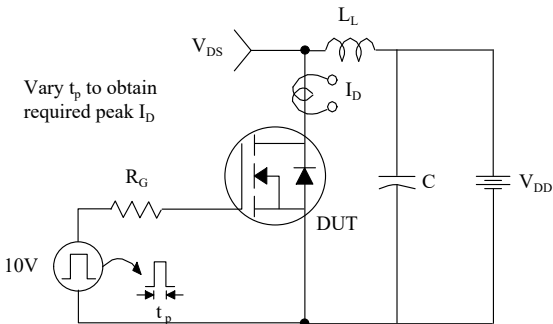
### Gate Charge Test Circuit & Waveform



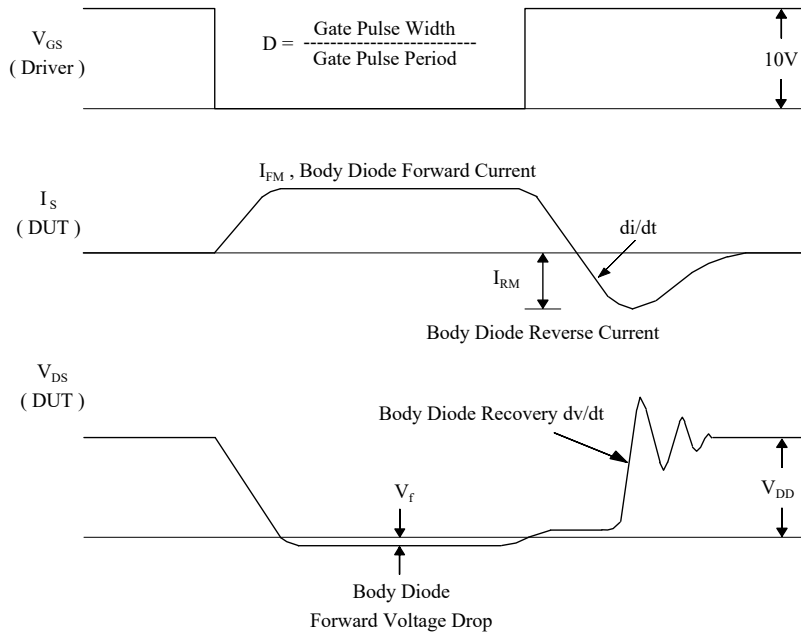
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



# Peak Diode Recovery dv/dt Test Circuit & Waveforms



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